Electronic Information Disclosure Statement

Ionic Pre-concentration XRF Detection and Analysis Device, System and Method

Application:

Confirmation:

Applicant(s):

Robert Keville

Docket

ISIP017US

Number:

Group Art Unit:

Examiner:

Unknown

search string:

(5192432 or 5200068 or 5360540 or 5415768 or 5425858 or 5538611 or 5547581 or 5620597 or

5779891 or 5834633 or 5945084 or 5954937).pn.

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

llinit	Citation No.	Patent Number	Date	Bar Code	Patentee	Class	Subclass
*	P01	5192432	1993-03-09		Andelman	204	665
	P02	5200068	1993-04-06	(111 11 1111111111111111111111111111111	Andelman	204	645
	P03	5360540	1994-11-01		Andelman	210	198.2
	P04	5415768	1995-05-16		Andelman	210	198.2
	POS	5425858	1995-06-20	1110 1100 1100 1100 1100 1100 1100 1100 1100 1100 1100 1100 1100 1100 1100 1100	Farmer	204	450
	P06	5538611	1996-07-23		Otowa	204	550
*	P07	5547581	1996-08-20	THE BUT SHEET STEED SHEET SHEE	Andelman	210	656

æ	P08	5620597	1997-04-15		Andelman	210	198.2
	P09	5779891	1998-07-14	1011 100 100 100 100 100 100 100 100 10	Andelman	210	198.2
	P10	5834633	1998-11-10		Davison	73	53.01
\prod	P11	5945084	1999-08-31		Droege	423	447.4
4	P12	5954937	1999-09-21	10181 100 1001 100 100 100 100 100 100 1	Farmer	205	687

Remarks

(Remarks are not for responding to an office action.)

All of the references cited in this information disclosure have already been discussed at length in the specification as filed. This discussion in the filed specification will be relied upon to provide a "concise explanation of relevance," which, of course, is nevertheless optional for English-language references. (See 37 CFR 1.98(a)(3) and MPEP 609 A(2) and A(3)).

Signature

Examiner Name	Date		
E_	5/4/04		